Message from the Program Chair

It gives me great pleasure to welcome you to the 1995 International Workshop on Defect and Fault Tolerance in VLSI Systems held in Lafayette, Louisiana.

The technical program includes 34 papers with authors representing eight countries. These papers are arranged in eight sessions covering topics such as Yield Projection and Critical Area Analysis, Defect Sensitivity, Fault Tolerance and Reliability, Testing, Self Checking and Coding Techniques.

The program also includes an invited talk on Intel’s experience with increasing die yield through CAD algorithms, and a panel discussion on the topic of tools for extraction of critical areas for yield analysis of VLSI design. I hope that you will find this year’s program a continuation of the previous DFT workshops’ tradition of excellence.

The success of a technical meeting such as this depends on the contribution and involvement of many individuals. First and foremost, we would like to thank all the authors who submitted their work to this workshop. I would like to express my gratitude to the members of the program committee and the external reviewers who contributed so much of their time and did a great job of providing in-depth reviews of the papers.

The administration of the technical program was almost fully automated, with all correspondence with authors, members of the program committee and external reviews done electronically. We even had an “electronic PC meeting” on the World Wide Web which allowed a larger number of program committee members to voice their opinion without having to travel. I wish to thank Zahava Koren, who provided tremendous help with the conference administration and the electronic communication.

Israel Koren
Program Chair
University of Massachusetts at Amherst